calculated margin is more indicative of the margin likely to prevail if the order were revoked, we determine that the original margins calculated in the Department's original investigation are probative of the behavior of Chinese producers and exporters of sebacic acid if the order were revoked. We will report to the Commission the companyspecific and all others rates contained in the Final Results of Review section of this notice.

Final Results of Review

As a result of this review, the Department finds that revocation of the antidumping order would likely lead to continuation or recurrence of dumping at the margins listed below: ⁵

Manufacturer/exporter	Margin (percent)
SINOCHEM Jiangsu Import & Export Corp	141.97
Tianjin Chemical Import & Export Corp	118.00
Chemical Co	82.66
port & Export Corp	102.99 243.40

This notice serves as the only reminder to parties subject to administrative protective order (APO) of their responsibility concerning the disposition of proprietary information disclosed under APO in accordance with 19 CFR 351.305 of the Department's regulations. Timely notification of return/destruction of APO materials or conversion to judicial protective order is hereby requested. Failure to comply with the regulations and the terms of an APO is a sanctionable violation.

This five-year ("sunset") review and notice are in accordance with sections 751(c), 752, and 777(i)(1) of the Act.

Dated: April 1, 1999.

Robert S. LaRussa,

Assistant Secretary for Import Administration.

[FR Doc. 99-8622 Filed 4-6-99; 8:45 am]

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DEPARTMENT OF COMMERCE

International Trade Administration

University of Michigan; Notice of Decision on Application for Duty-Free Entry of Scientific Instrument

This is a decision pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, N.W., Washington, D.C.

Docket Number: 99–001. Applicant: The Regents of the University of Michigan, Ann Arbor, MI 48109–0602. Instrument: Electron Microscope, Model H–7500. Manufacturer: Hitachi Scientific Instruments, Japan. Intended Use: See notice at 64 FR 9981, March 1, 1999. Order Date: April 23, 1998.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as the instrument is intended to be used, was being manufactured in the United States at the time the instrument was ordered. Reasons: The foreign instrument is a conventional transmission electron microscope (CTEM) and is intended for research or scientific educational uses requiring a CTEM. We know of no CTEM, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of the instrument.

Frank W. Creel.

Director, Statutory Import Programs Staff. [FR Doc. 99–8619 Filed 4–6–99; 8:45 am] BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

International Trade Administration

Application for Duty-Free Entry of Scientific Instrument

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89–651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether an instrument of equivalent scientific value, for the purposes for which the instrument shown below is intended to be used, is being manufactured in the United States

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington,

D.C. 20230. Application may be examined between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th Street and Constitution Avenue, N.W., Washington, D.C.

Docket Number: 99–003. Applicant: Louisiana State University, Mechanical Engineering Department, Nicholson Ext., Baton Rouge, LA 70803. *Instrument:* Electron Microscope, Model JEM-2010. Manufacturer: JEOL Ltd., Japan. *Intended Use:* The instrument will be used extensively in the study of microstructures, surfaces, and the structural and compositional characteristics of materials. The research areas of interest include but are not limited to the following: (1) fundamental issues of stress corrosion cracking phenomena and specifically directed toward understanding the nature of the embrittlement mechanism, (2) surface modification processes and more specifically with the processingmicrostructure-property relationship of modified surfaces and thin films, (3) exploring the possibility to grow thick amorphous alloy layers by solid-state interdiffusion reactions in diffusion couples assisted by bombardment of energetic particles (plasma or ion beam), (4) understanding how and why solidstate alloying and amorphization can be achieved in some binary systems with relatively large positive heat of mixing (i.e., systems immiscible in equilibrium) and (5) studying the consolidation and properties of nanocrystalline metals, oxides and noncomposites. Application accepted by Commissioner of Customs: March 19, 1999.

Frank W. Creel,

Director, Statutory Import Programs Staff. [FR Doc. 99–8620 Filed 4–6–99; 8:45 am] BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

International Trade Administration

Request for Comments on the Asian Pacific Economic Cooperation (APEC) Electronic Commerce Steering Group Work Plan

AGENCY: International Trade Administration, Commerce.

ACTION: Notice of request for public comment.

SUMMARY: The Department of Commerce/International Trade Administration (DOC/ITA) seeks comment on the APEC Electronic Commerce Steering Group work program.

DATES: Comments are due no later than April 21, 1999.

⁵The margins in this section of the notice reflect the changes to the original margins pursuant to court remand (see Final Results of Redetermination Pursuant to Court Remand, Union Camp Corporation v. United States, Consol. Court No. 94–08–00480, Slip Op. 96–123 (August 5, 1996)).